

N-channel TrenchMOS FET

Rev. 02 — 28 September 2010

Product data sheet

1. Product profile

1.1 General description

Standard and logic level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Engine management
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	75	V
I _D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ see <u>Figure 1</u>	-	-	74	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	158	W
Static char	racteristics					
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _i = 25 °C; see <u>Figure 11</u>	-	9.3	11	mΩ



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 Table 1.
 Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$I_D = 74 \text{ A}; V_{sup} \le 75 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 ^{\circ}\text{C}; \text{ unclamped}$	-	-	127	mJ
Dynamic c	Dynamic characteristics					
Q_{GD}	gate-drain charge	$I_D = 25 \text{ A}$; $V_{DS} = 60 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 13; see Figure 14	-	30	-	nC

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		
mb	D	mounting base; connected to drain	1 3	mbb076 S
			SOT428 (DPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK6211-75C	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428



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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	75	V
V_{GS}	gate-source voltage	DC	<u>[1]</u>	-16	16	V
		Pulsed	[2]	-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>		-	74	Α
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>		-	52	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \mu s$; pulsed; see <u>Figure 3</u>		-	297	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	158	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	diode					
Is	source current	T _{mb} = 25 °C		-	74	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	297	Α
Avalanche rug	ggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 74 A; $V_{sup} \le$ 75 V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	127	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		[3][4][5]	-	-	J

^{[1] -16}V accumulated duration not to exceed 168 hrs.

^[2] Accumulated pulse duration not to exceed 5 mins.

^[3] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

^[4] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

^[5] Refer to application note AN10273 for further information.

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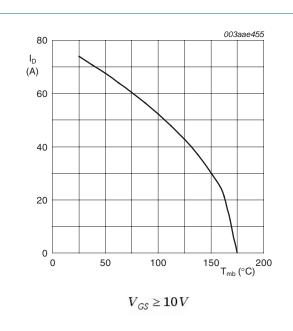


Fig 1. Continuous drain current as a function of mounting base temperature

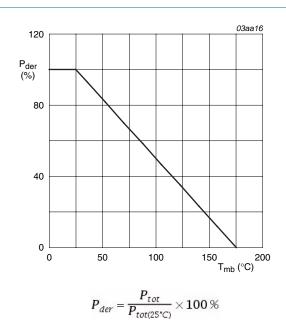
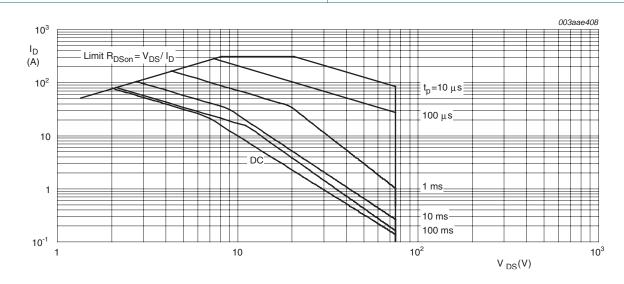


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is a single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.95	K/W

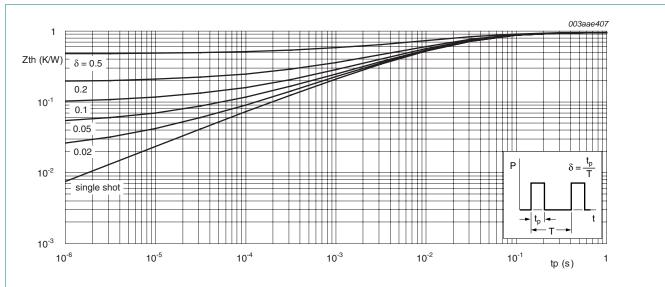


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration



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6. Characteristics

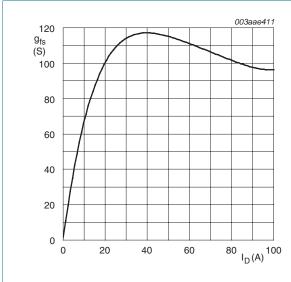
Table 6. Characteristics

Symbol	Parameter Parameter	Conditions	Min	Тур	Max	Unit
•	racteristics	Conditions	141111	יאָני	max	Jiiit
	drain-source breakdown	I _D = 250 μA; V _{GS} = 0 V; T _i = 25 °C	75	_	_	V
$V_{(BR)DSS}$	voltage	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}, T_j = 25 \text{C}$ $I_D = 250 \mu\text{A}; V_{GS} = 0 \text{V}; T_i = -55 \text{°C}$	68		-	V
V	gate-source threshold voltage	· · · · · · · · · · · · · · · · · · ·	1.8	2.3	2.8	V
V _{GS(th)}	gate-source theshold voltage	see Figure 9; see Figure 10	1.0	2.3		
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 9	-	-	3.3	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 175 \text{ °C}$; see Figure 9	8.0	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 75 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		V _{DS} = 75 V; V _{GS} = 0 V; T _j = 25 °C	-	0.02	1	μΑ
I_{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 20 \text{ V}; T_j = 25 \text{ °C}$	-	5	100	nA
		V _{DS} = 0 V; V _{GS} = -20 V; T _j = 25 °C	-	5	100	nΑ
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 11	-	9.3	11	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 11	-	11	15	mΩ
		$V_{GS} = 5 \text{ V; } I_D = 25 \text{ A; } T_j = 25 \text{ °C;}$ see Figure 11	-	10.4 13.2	13.2	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 175 °C;$ see Figure 12	-	-	28.6	mΩ
Dynamic o	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}$; $V_{DS} = 60 \text{ V}$; $V_{GS} = 5 \text{ V}$; see Figure 13; see Figure 14	-	52	-	nC
		I _D = 25 A; V _{DS} = 60 V; V _{GS} = 10 V; see Figure 14; see Figure 13	-	81	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 60 \text{ V}; V_{GS} = 10 \text{ V};$	-	11	-	nC
Q _{GD}	gate-drain charge	see Figure 13; see Figure 14	-	30	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	3938	5251	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	310	372	pF
C _{rss}	reverse transfer capacitance		-	206	282	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 55 \text{ V}; R_L = 2.2 \Omega; V_{GS} = 10 \text{ V};$	-	18	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega$	-	40	-	ns
t _{d(off)}	turn-off delay time		-	165	-	ns
t _f	fall time		-	80	-	ns
L _D	internal drain inductance	from upper edge of drain mounting base to centre of die; T _i = 25 °C	-	3.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad ; T _i = 25 °C	-	7.5	-	nΗ

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Table 6. Characteristics ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dra	in diode					
V _{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see Figure 15	-	0.8	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	50.5	-	ns
Q _r	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}$	-	105	-	nC



 $T_j = 25 \,^{\circ}C; V_{DS} = 25 V$

Fig 5. Forward transconductance as a function of drain current; typical values

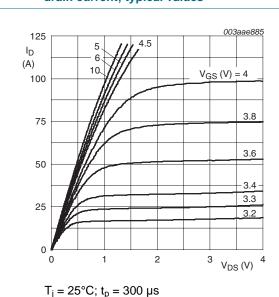


Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values

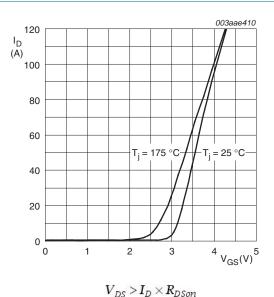
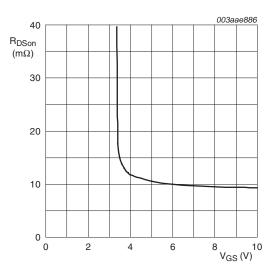


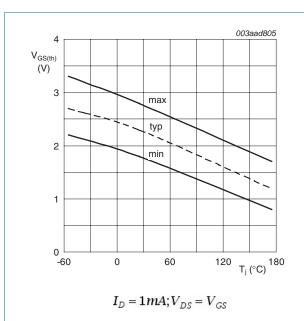
Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_i = 25^{\circ}C; I_D = 25 A$

Fig 8. Drain-source on-state resistance as a function of gate-source voltage; typical values

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Gate-source threshold voltage as a function of Fig 9. junction temperature

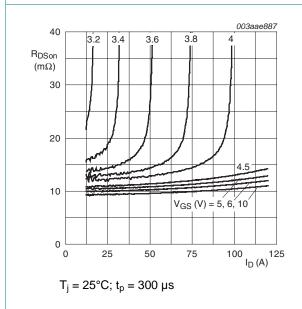
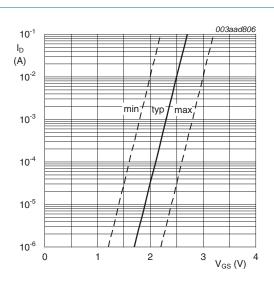


Fig 11. Drain-source on-state resistance as a function of drain current; typical values



 $T_j = 25 \,^{\circ}C; V_{DS} = 5V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage

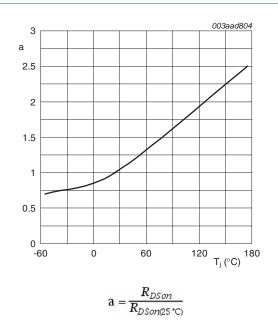
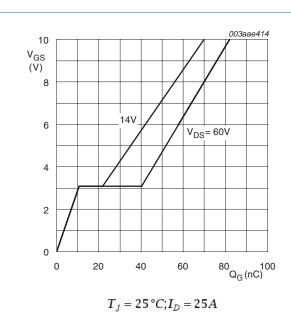


Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

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V_{GS}(pl)
V_{GS}(th)
V_{GS}
Q_{GS1} Q_{GS2}
Q_G(tot)
003aaa508

Fig 13. Gate-source voltage as a function of gate charge; typical values

Fig 14. Gate charge waveform definitions

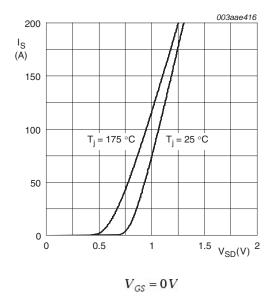


Fig 15. Source current as a function of source-drain voltage; typical values



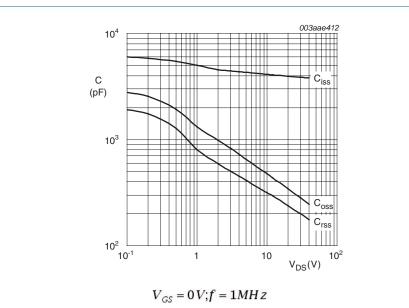


Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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7. Package outline

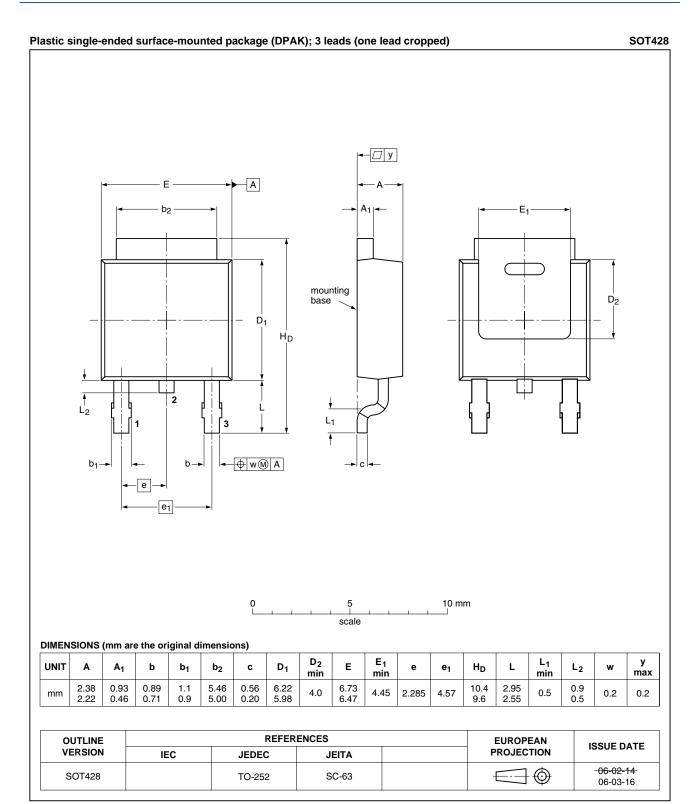


Fig 17. Package outline SOT428 (DPAK)



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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK6211-75C v.2	20100928	Product data sheet	-	BUK6211-75C v.1
Modifications:	Status changeVarious change	d from objective to product. es to content.		
BUK6211-75C v.1	20100908	Objective data sheet	-	-

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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